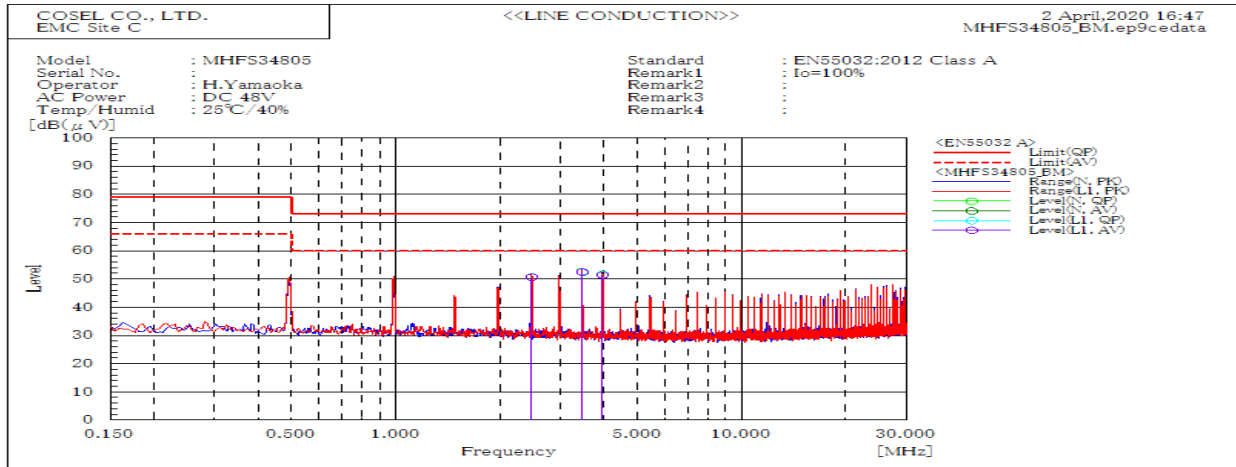
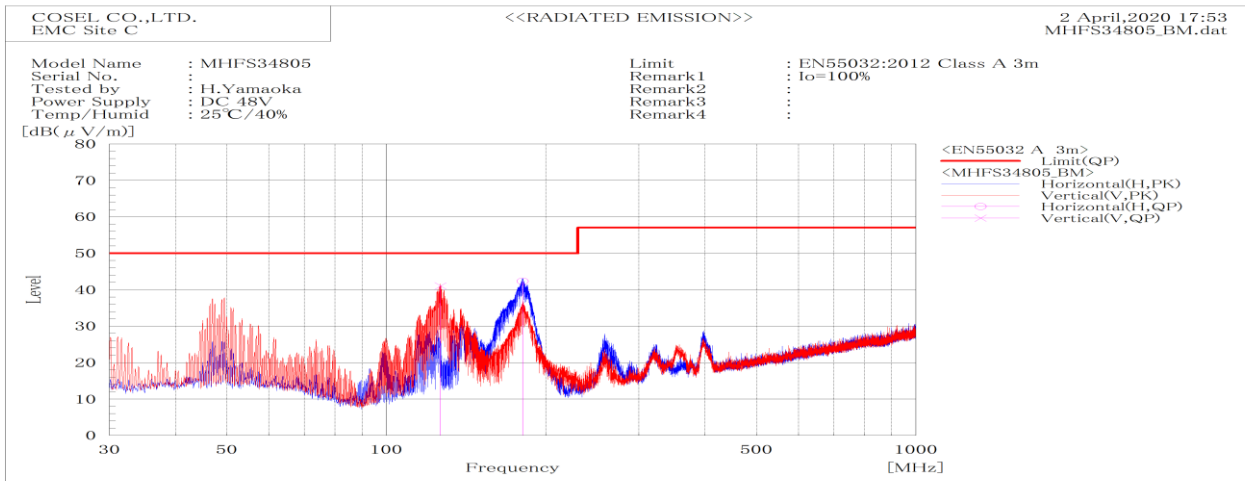


DATA SHEET		Date	04-Jun-20
Model	MHFS34805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka



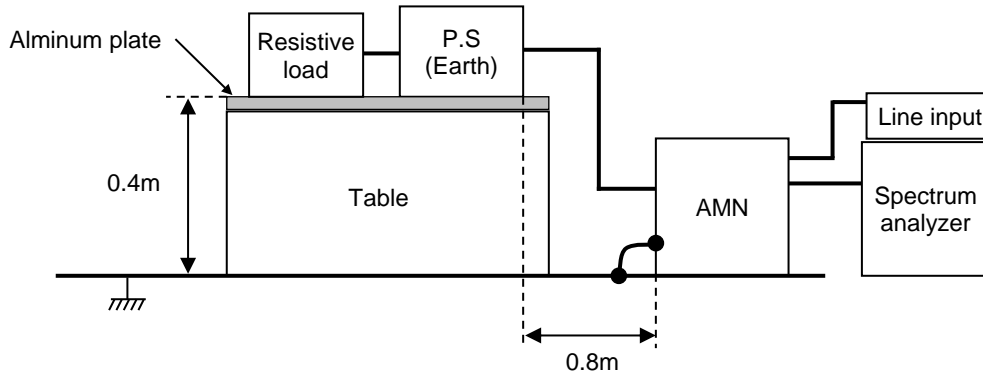
Frequency MHz	Line	Level dB(µV)		Limit dB(µV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
2.473	N	50.7	50.6	73	60	22.3	9.4	Pass	
3.461	N	52.7	52.6	73	60	20.3	7.4	Pass	
3.956	N	51.6	51.5	73	60	21.4	8.5	Pass	
2.472	L1	50.7	50.7	73	60	22.3	9.3	Pass	
3.461	L1	52.5	52.5	73	60	20.5	7.5	Pass	
3.955	L1	51.5	51.4	73	60	21.5	8.6	Pass	



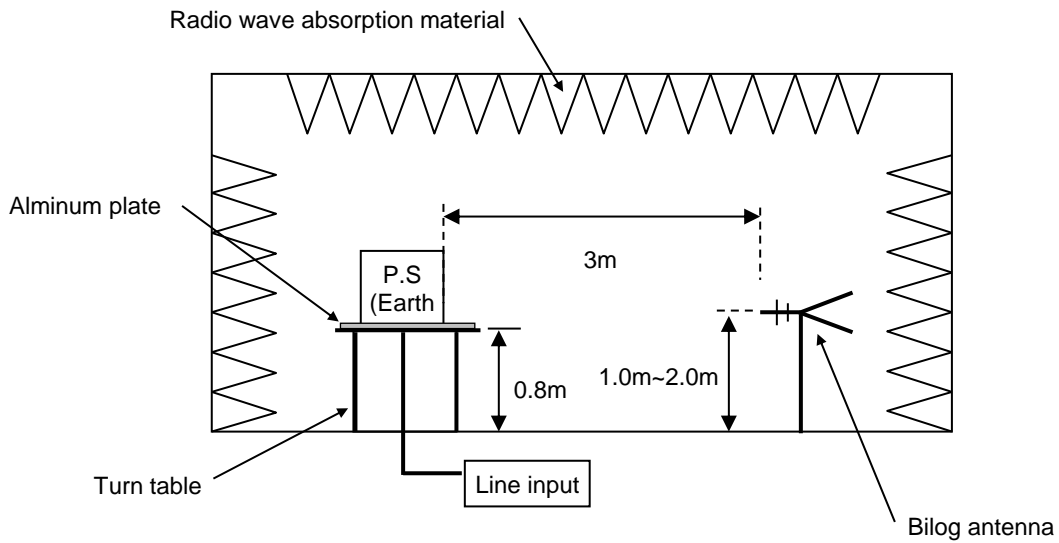
Frequency MHz	Polarization	Stability	Level dB(µV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
181.008	H	Stable	42.3	50	7.7	Pass	198.2	0	
126.614	V	Stable	41	50	9	Pass	117.8	91.7	

DATA SHEET		Date	04-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Yamaoka

1. Line conduction



2. Radiated emission

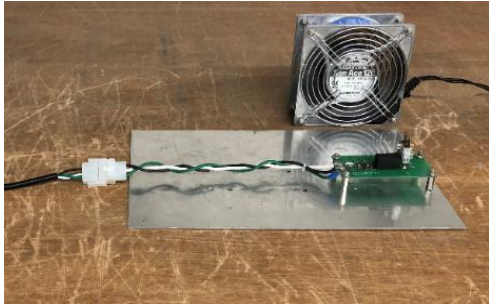


Conditions

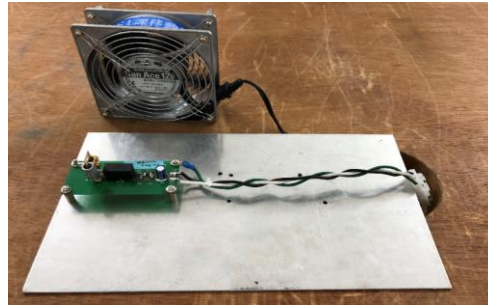
Test : EMI
 Model Name: MHFS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

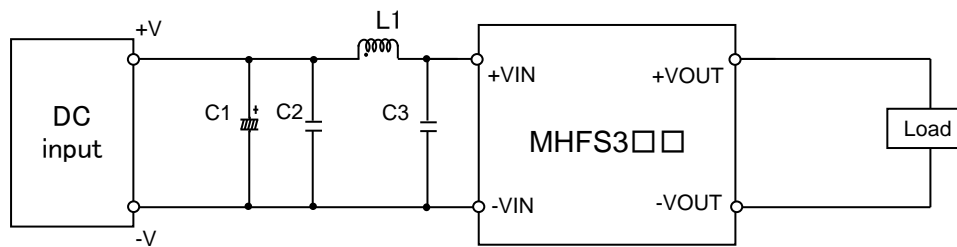


Fig.1 Testing circuitry

C1 :	MHFS312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS324□□	-
	MHFS348□□	-
C2 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFS324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFS348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)